

Dual P-Channel 60-V (D-S) MOSFET

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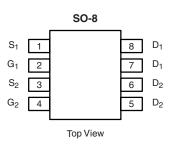
PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω) Typ.	I _D (A) ^d	Q _g (TYP.)			
-60	0.066 at V _{GS} = -10 V	-5.0	10.1 nC			
	0.070 at V_{GS} = -4.5 V	-4.0	10.1110			

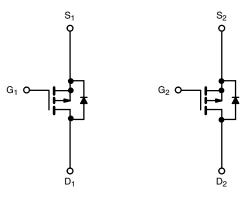
FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET



Compliant to RoHS Directive 2002/95/EC





P-Channel MOSFET

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ABSOLUTE MAXIMUM RATINGS (TA =	= 25 °C, unless other	wise noted)			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	-60	V		
Gate-Source Voltage	V _{GS}	± 20	V		
	T _C = 25 °C		-5.0		
	T _C = 70 °C		-4.0		
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	T _A = 25 °C	I _D	-3.8 ^{a,b}		
	T _A = 70 °C		-3.1 ^{a,b}		
Pulsed Drain Current (t = 100 µs)	I _{DM}	-25	Α		
	T _C = 25 °C		-3.9		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	-2.1 ^{a,b}		
Avalanche Current		I _{AS}	-15		
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	11.25	mJ	
	T _C = 25 °C		4.2		
Manimum Danier Dissis ation	T _C = 70 °C		2.7	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	2 ^{a,b}	vv	
	T _A = 70 °C	1	1.3 ^{a,b}		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Mauinum lunation to Ambienta	t ≤ 10 s	R _{thJA}	53	62.5		
Maximum Junction-to-Ambient ^a	Steady State		85	110	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	30	37		

Notes

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under steady state conditions is 110 °C/W.

d. Based on T_C = 25 °C.

VBA4670

SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$,	SYMBOL	,	MIN	TVD	MAY	LINUT	
PARAMETER	STMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static	• • •			-		L	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = -250 μA	-60	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = -250 μA	-	-6.7	-	- mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		-	-4.3	-		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	-0.5	-	-2.5	V	
Gate-Source Leakage	I _{GSS}	V_{DS} = 0 V, V_{GS} = ± 20 V		-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V_{DS} = -60 V, V_{GS} = 0 V	1		-1	μA	
	.033	$V_{DS} = -60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$	-	-	-5	-5	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge$ -10 V, V_{GS} = -10 V	-30	-	-	А	
Drain-Source On-State Resistance ^a	Brach	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -3.5 \text{ A}$	-	0.066	-	Ω	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -2.8 \text{ A}$	-	0.070	-		
Forward Transconductance ^a	9 _{fs}	$V_{DS} = -30 \text{ V}, \text{ I}_{D} = -3.5 \text{ A}$	-	11	-	S	
Dynamic ^b						-	
Input Capacitance	C _{iss}		-	832	-	pF	
Output Capacitance	C _{oss}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	-	88	-		
Reverse Transfer Capacitance	C _{rss}		-	63	-		
Tabal Oaks Okasas	0	V_{DS} = -30 V, V_{GS} = -10 V, I_{D} = -3.5 A	-	20	30	nC	
Total Gate Charge	Q _g		-	10.1	15.2		
Gate-Source Charge	Q _{gs}	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -3.5 \text{ A}$	-	3.3	-		
Gate-Drain Charge	Q _{gd}		-	3.9	-		
Gate Resistance	R _g	f = 1 MHz	1.8	9	18	Ω	
Turn-On Delay Time	t _{d(on)}		-	8	16	+	
Rise Time	t _r	$V_{DD} = -30 \text{ V}, \text{ R}_1 = 10.7 \Omega$	-	6	12		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ -2.8 A, V_{GEN} = -10 V, R_g = 1 Ω	-	35	53		
Fall Time	t _f		-	16	24		
Turn-On Delay Time	t _{d(on)}		-	40	60	ns	
Rise Time	t _r	$V_{DD} = -30 \text{ V}, \text{ R}_{\text{I}} = 10.7 \Omega$	-	28	42	-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -2.8$ A, $V_{GEN} = -4.5$ V, $R_g = 1 \Omega$	-	31	47		
Fall Time	t _f		-	15	23		
Drain-Source Body Diode Characterist	ics	L	1	L			
Continous Source-Drain Diode Current	Is	T _C = 25 °C	-	-	-3.5		
Pulse Diode Forward Current (t = 100 µs)	I _{SM}		-	-	-20	A	
Body Diode Voltage	V _{SD}	I _S = -2.8 A, V _{GS} = 0 V	-	-0.85	-1.2	V	
Body Diode Reverse Recovery Time	t _{rr}		-	32	48	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$\begin{array}{c} \overline{P_{rr}} \\ I_F = -2.8 \text{ A}, \text{ dl/dt} = 100 \text{ A/}\mu\text{s}, \\ T_J = 25 \text{ °C} \end{array}$		45	68	nC	
Reverse Recovery Fall Time	t _a			24	-		
Reverse Recovery Rise Time	t _b			8	-	ns	

Notes

a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

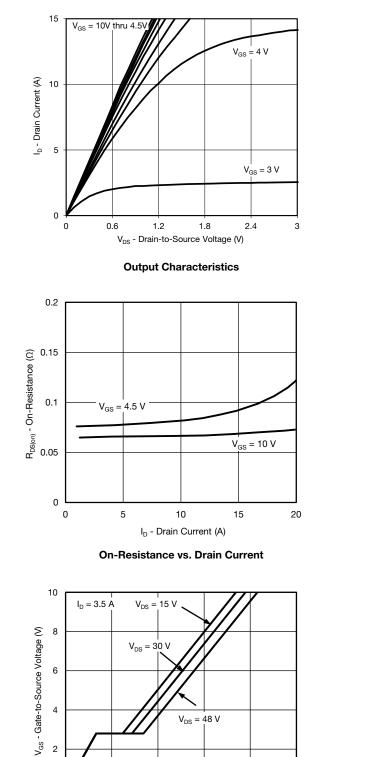
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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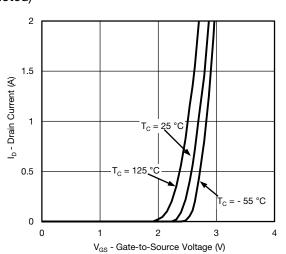


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

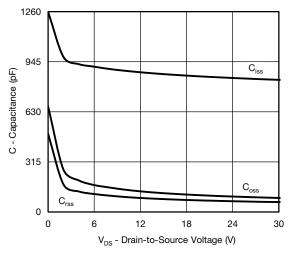


Q_g - Total Gate Charge (nC)

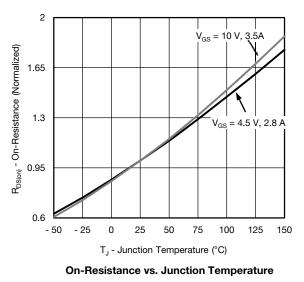
 $V_{DS} = 48 V$



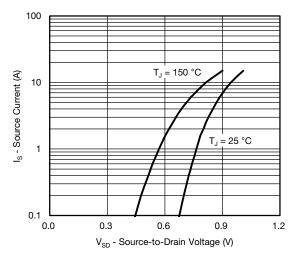
Transfer Characteristics



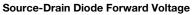


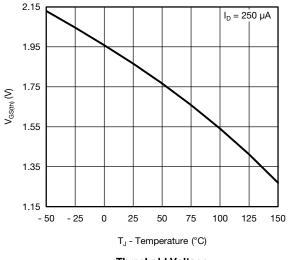




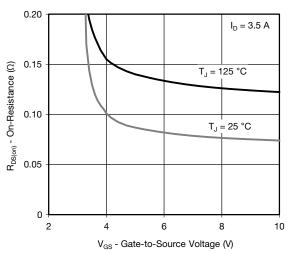


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

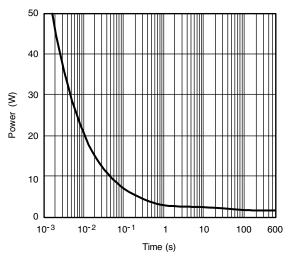




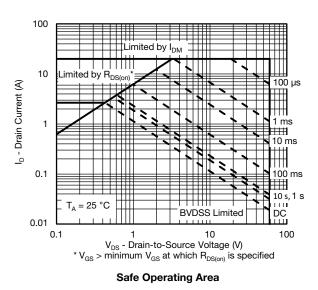
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

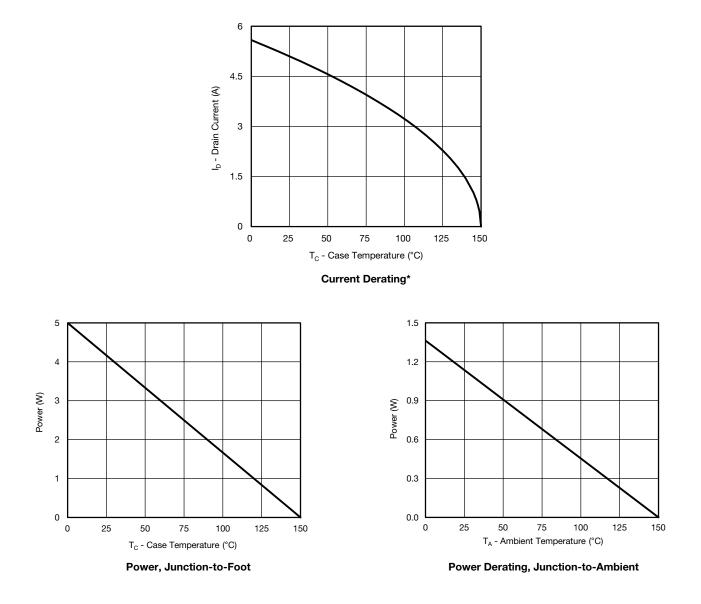


Single Pulse Power, Junction-to-Ambient





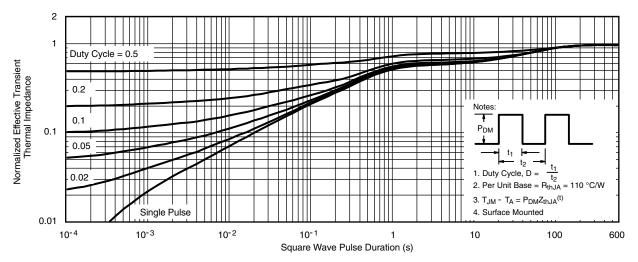
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



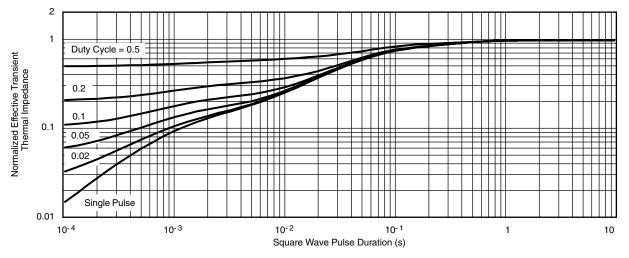
* The power dissipation P_D is based on $T_{J (max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.







Normalized Thermal Transient Impedance, Junction-to-Ambient

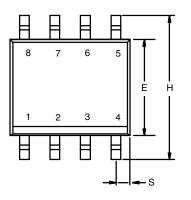


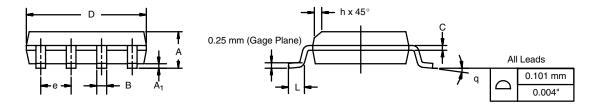
Normalized Thermal Transient Impedance, Junction-to-Foot





SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012

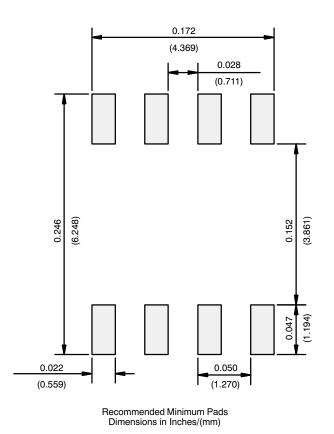




	MILLIMETERS		INCHES			
DIM	Min	Мах	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27 BSC		0.050 BSC			
н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8





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